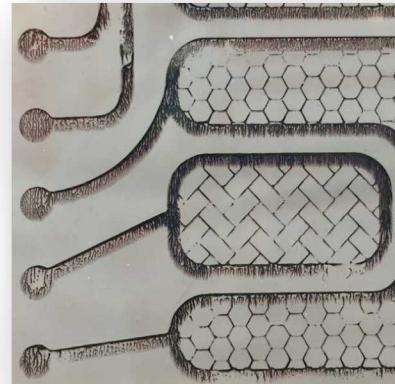
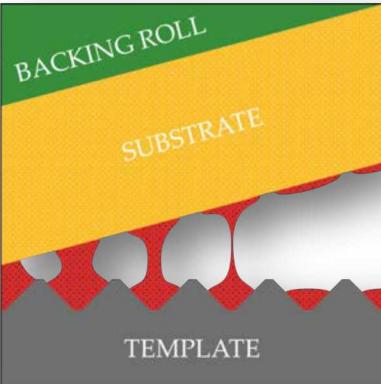
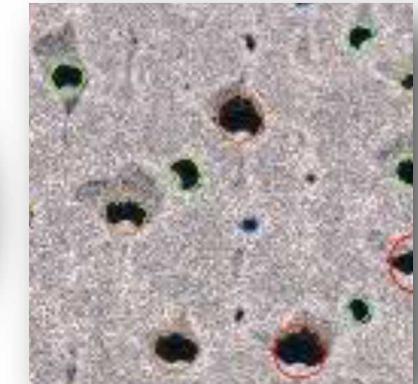
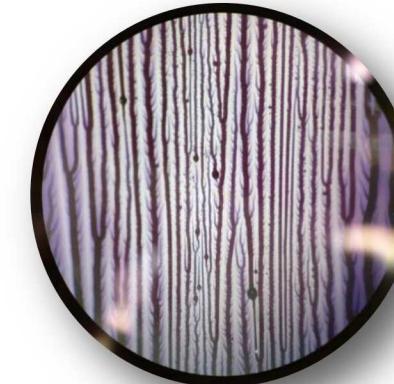


# GRAVURE PRINTING DEFECT PREDICTION VIA MACHINE LEARNING



Robert Malakhov  
Kristianto Tjiptowidjojo  
Randy Schunk\*  
2020 August 4th



\*Materials, Chemical, and Physical Sciences Center, Sandia National Laboratories, Albuquerque, NM

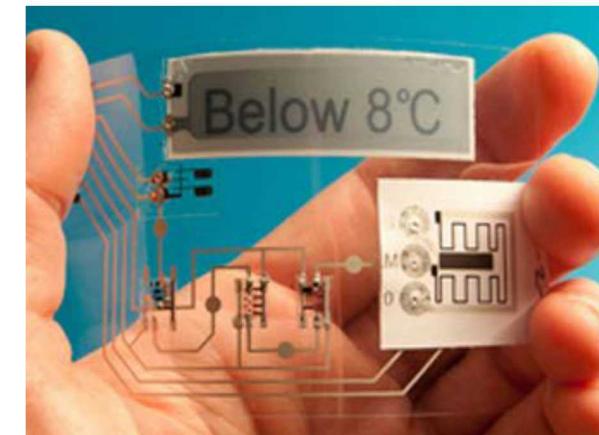
Sandia National Laboratories is a multimission laboratory managed and operated by National Technology and Engineering Solutions of Sandia, LLC, a wholly owned subsidiary of Honeywell International Inc., for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-NA0003525.

# ENABLING THE FUTURE

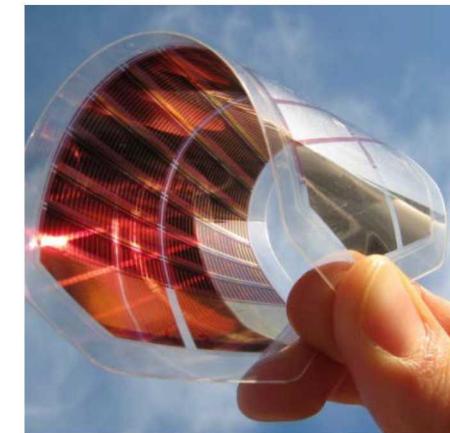
- Printed Electronics and Flexible Systems enable future innovations and applications
  - Low cost sensors in smart and connected devices (Internet of Things (IoT))
  - Smart-packaging, RFID tags
  - Healthcare wearable devices
  - Flexible displays
  - Organic Photovoltaics
  - \$9.8 billion (2019)  
\$19.8 billion (2024)  
(2019 Markets and Markets)



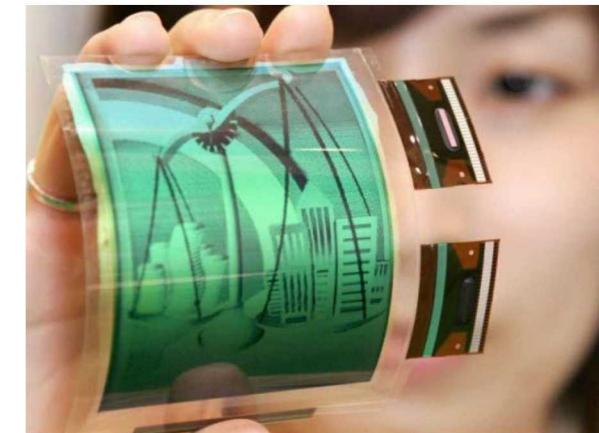
SENSORS



PRINTABLE ELECTRONICS



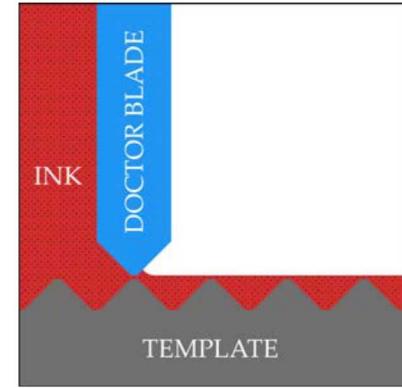
ORGANIC PHOTOVOLTAICS



FLEXIBLE SCREENS

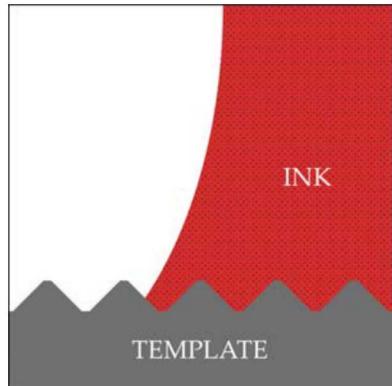
Challenge lies in understanding complex physical mechanisms to generate smaller features

# GRAVURE PRINTING PROCESS

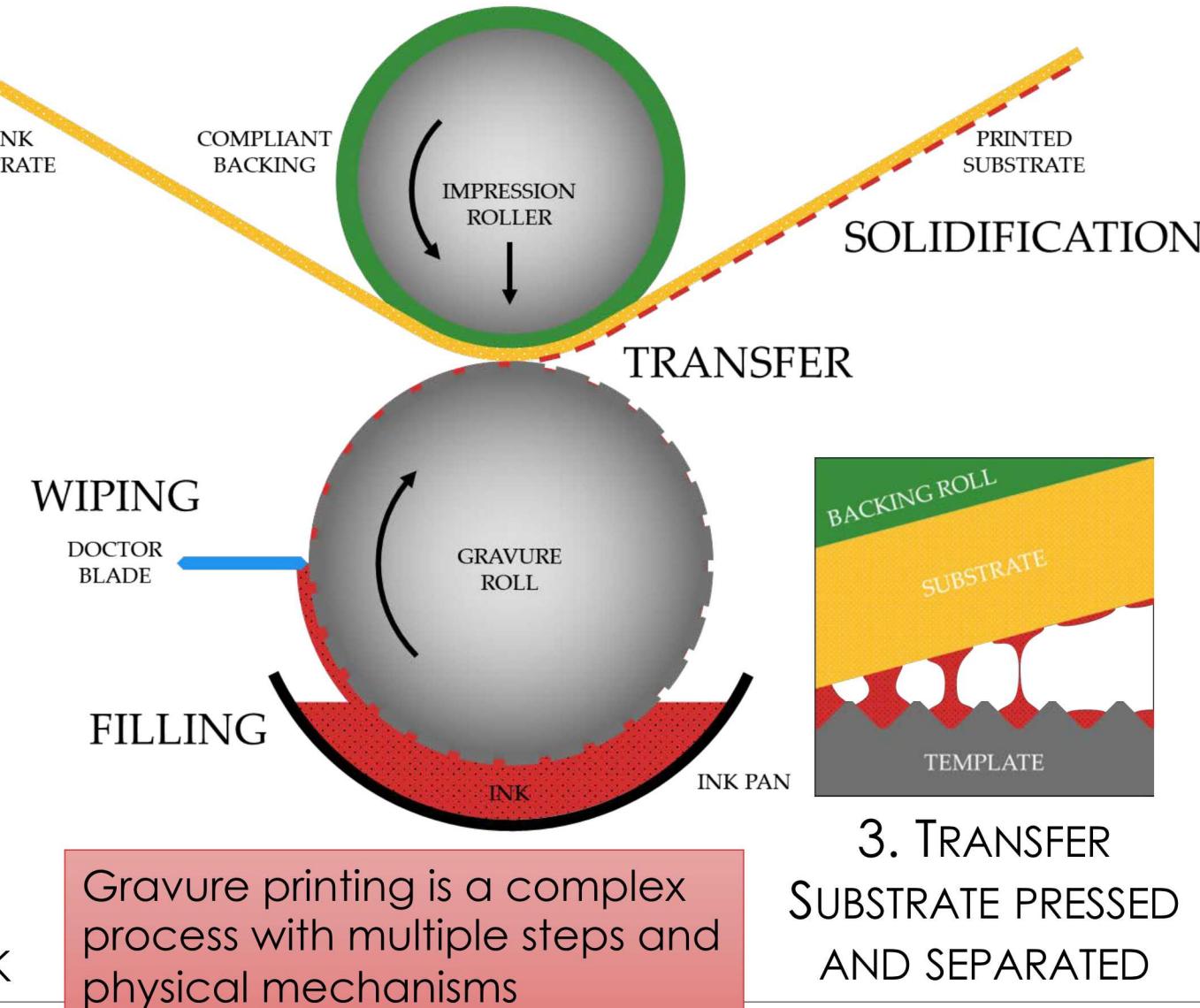


## 1. FILLING

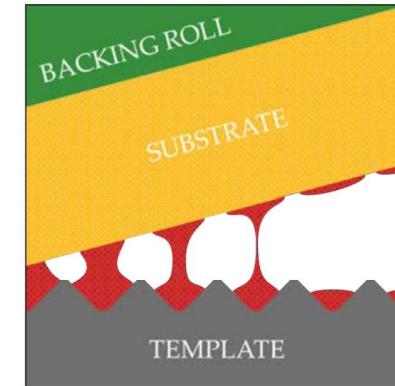
CELLS FILLED WITH INK



BLADE REMOVES EXCESS  
INK



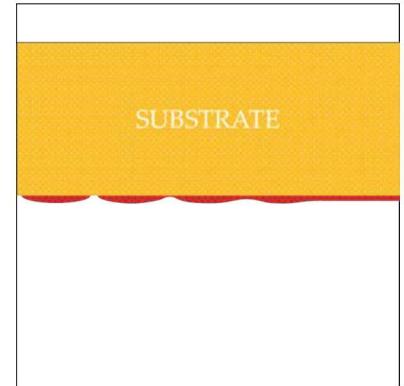
## 3. TRANSFER SUBSTRATE PRESSED AND SEPARATED



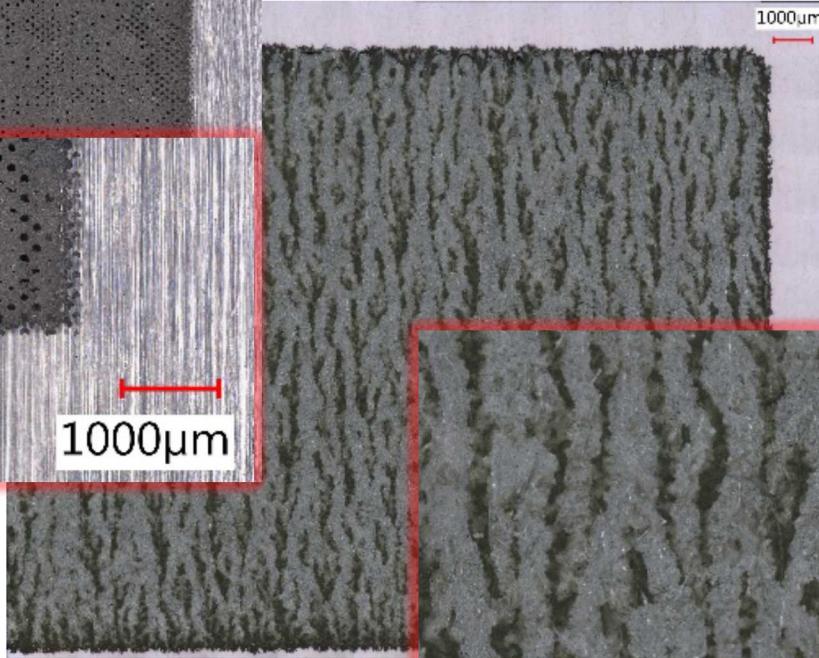
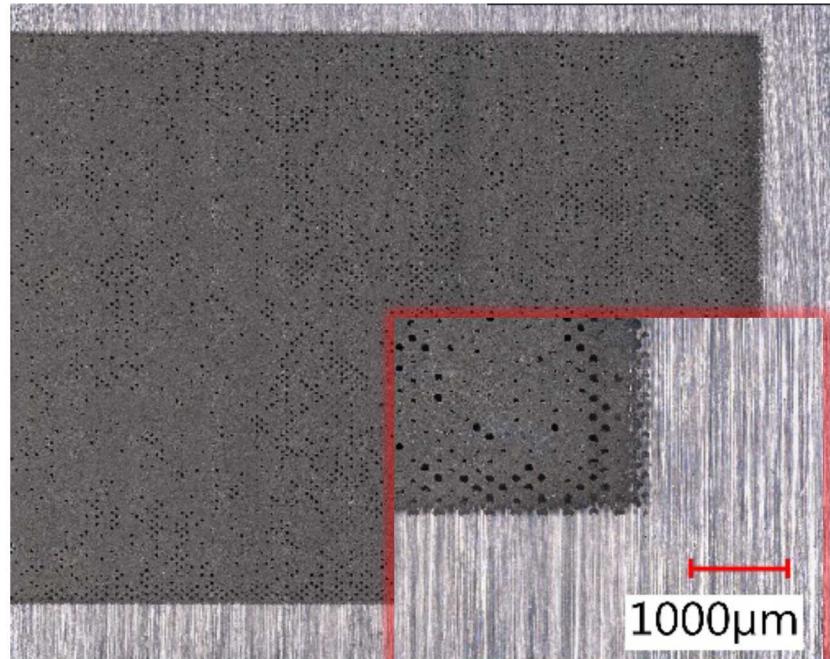
## 4. SOLIDIFICATION

**Ideal for PE:**

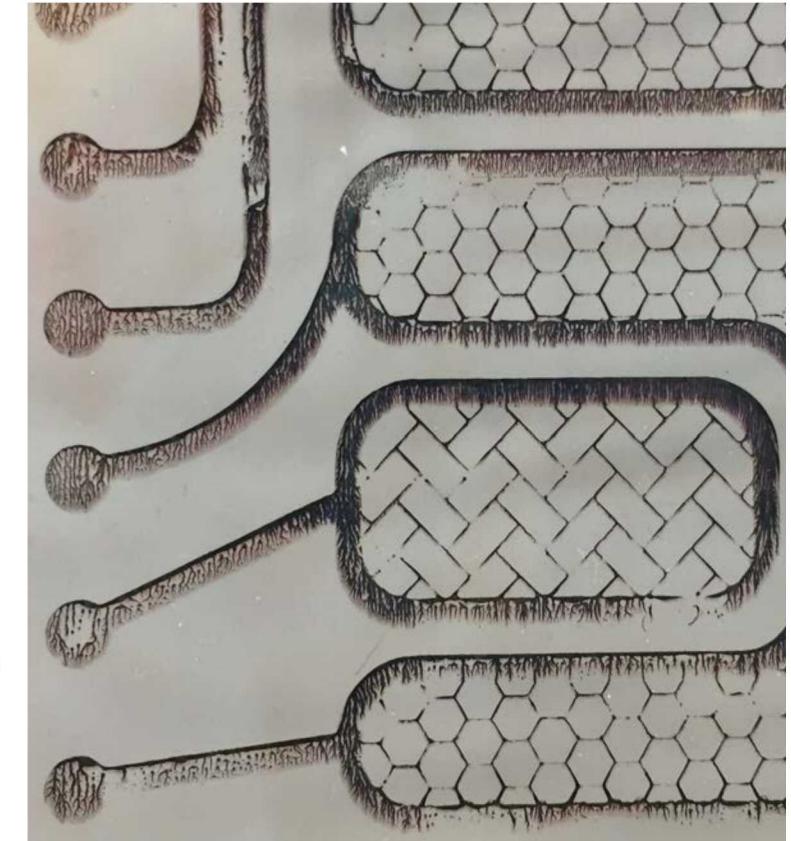
- + Over wide areas
- + High throughput
- + Durable
- + Wide solvent compatibility
- + Combine with other mechanisms
- + **Pattern resolution**
- + **Print speed**
- Overlay and registration is challenging



# DEFECTS LEAD TO PERFORMANCE DISRUPTION



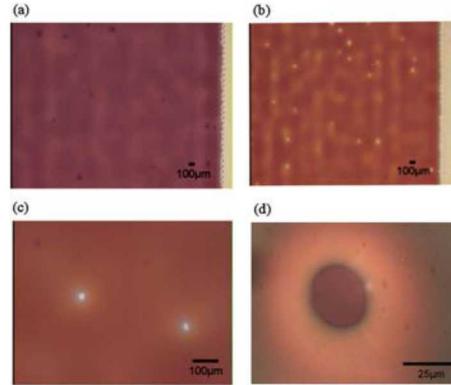
What is the cause  
of these defects?



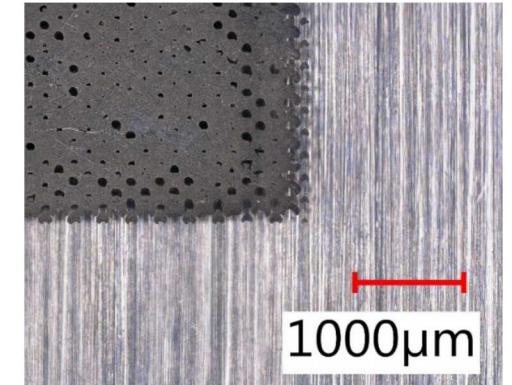
# PINHOLES: NOT ALL PINHOLES ARE THE SAME

- May be controlled for
  - Template defects
  - Ink impurities
  - Missing particulate
  - Irregular template contact
  - Environmental contaminants
- Less understood
  - Ink spreading / leveling
  - Gravure cell gas trapping

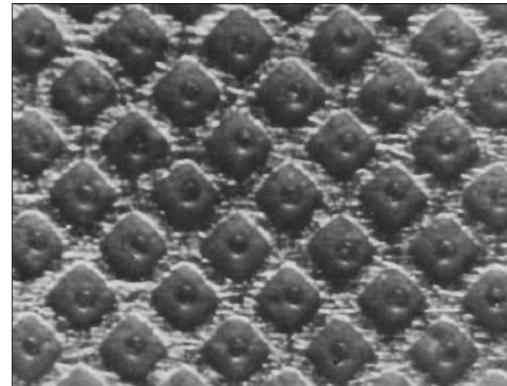
What is the cause of these process-based pinholes?



MISSING DOTS 2015 APILO ET AL.



NOT ENOUGH INK SPREADING



GAS TRAPPING 1985 BERY ET AL.



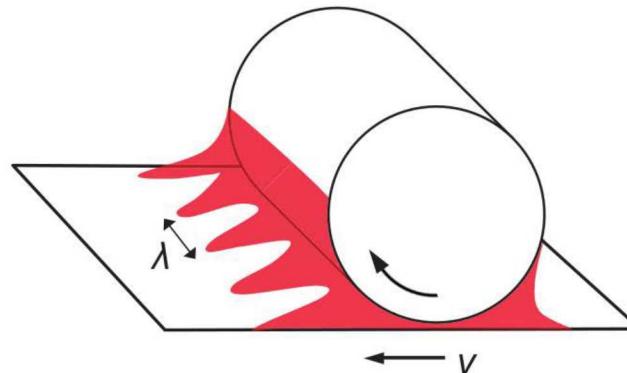
ENVIRONMENTAL CONTAMINANTS

# STRIATIONS: VISCOUS FINGERING VS RIBBING

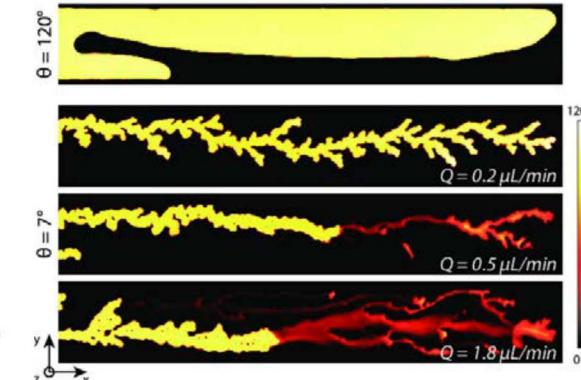
What is the cause of these striations?

## Viscous Fingering

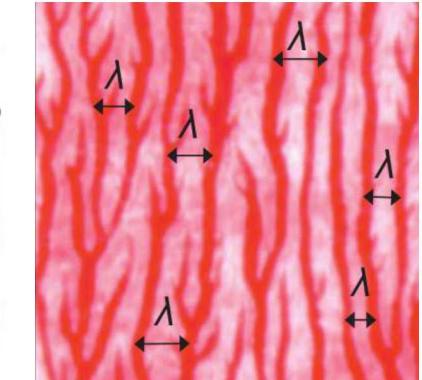
- Brumm et al. speculated due to viscous fingering
- Upstream transfer nip instabilities generate air fingers that index striations
- Can only occur in transfer nip where gas can be entrained



2019 BRUMM ET AL.



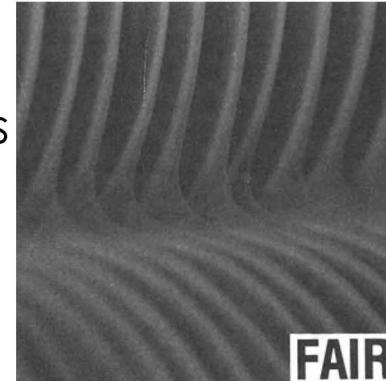
2014 LEVANCHE ET AL.



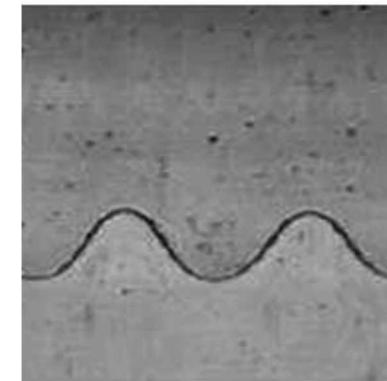
2019 BRUMM ET AL.

## Ribbing

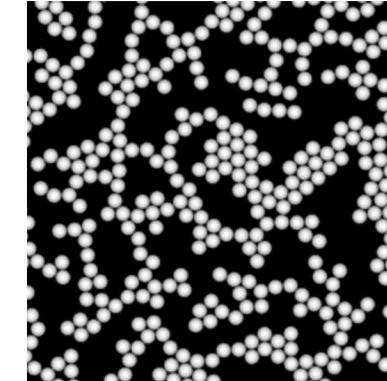
- May be due to instability common in separating flows
- Ribbing instability leads to peaks and troughs that drive differential drying and colloidal aggregation that index striations



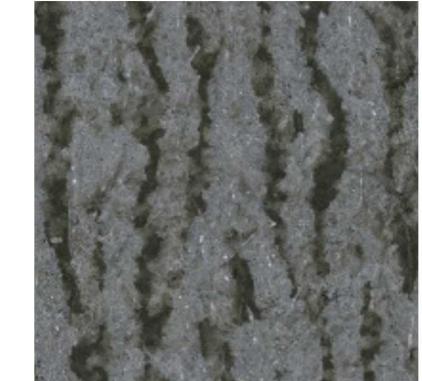
1988 SOULES ET AL.



2002 VARELA LOPEZ ET AL.

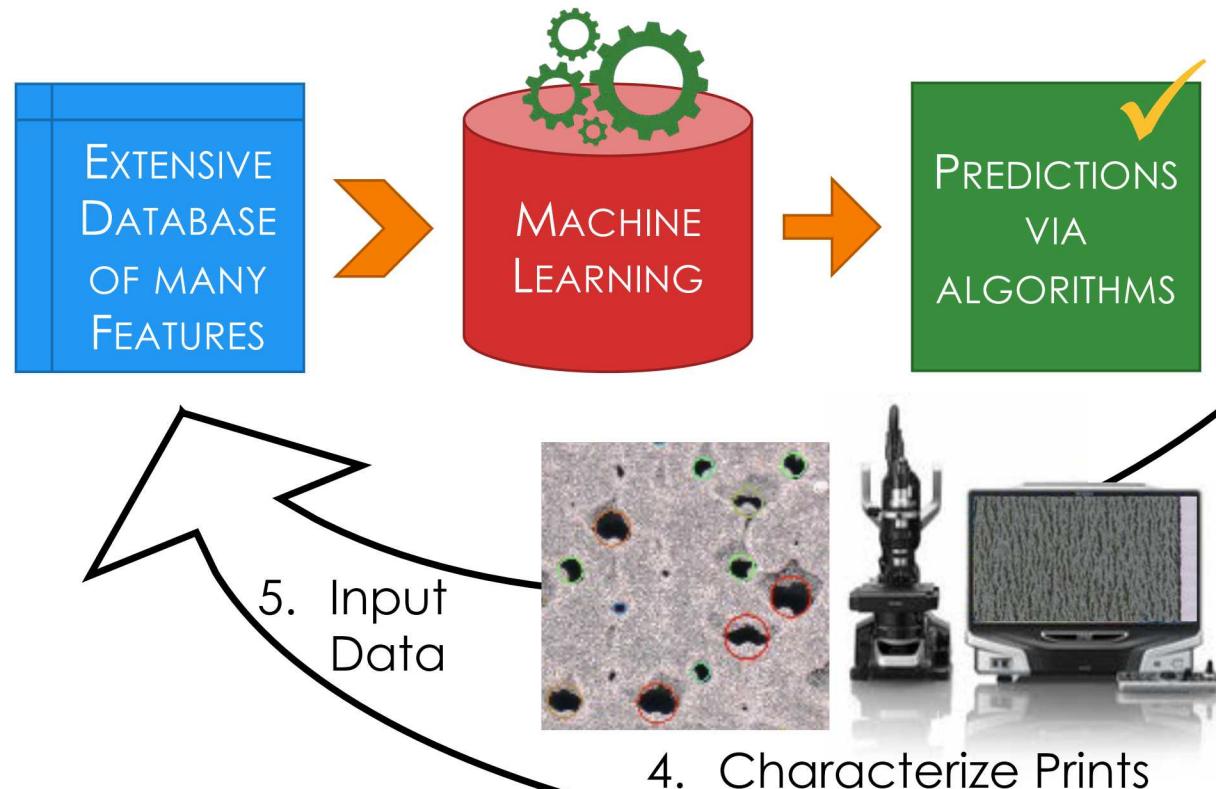


2007 FUJITA ET AL.

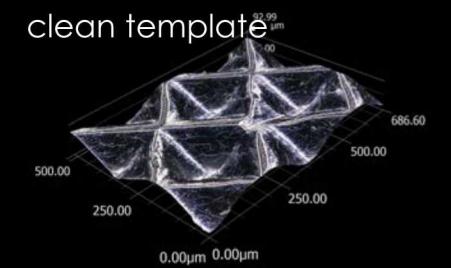
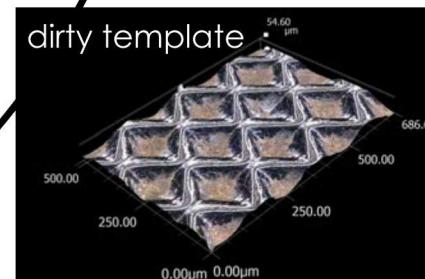


# INFORMATICS APPROACH & RESULTS COLLECTION

Gravure is a complex process so use machine learning to see big picture!



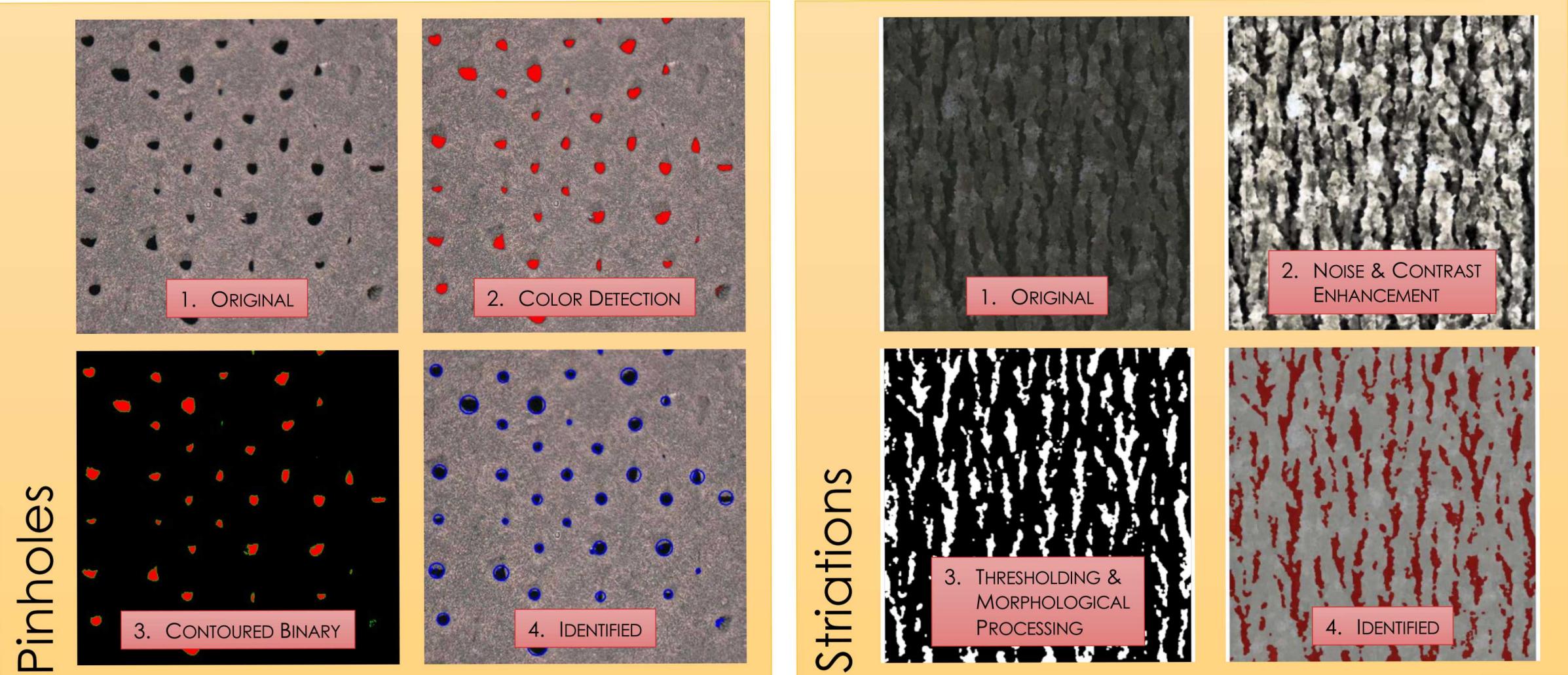
1. Print Sample



2. Clean Template

3. Dry with minimal dust and handling

# CHARACTERIZATION VIA COMPUTER VISION



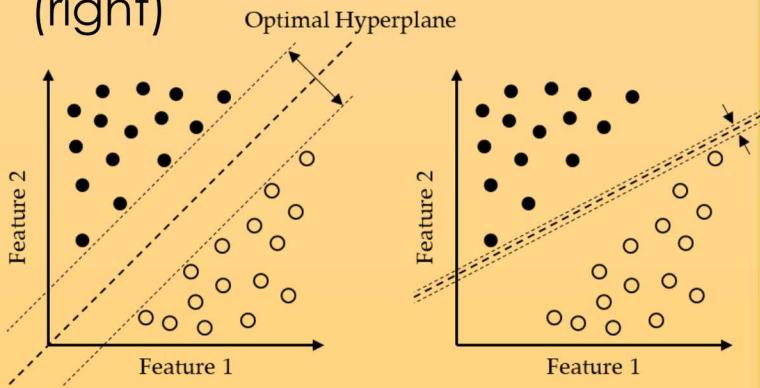
# ML ALGORITHMS

Learn which features are most sensitive and which set of features is enough to accurately predict defects

## Support Vector Machine (SVM)

Separates data into groups (classifications) in n-dimensional feature space

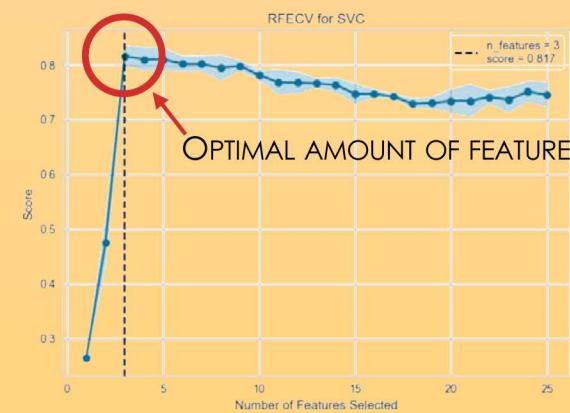
Uses the large margin principle to find a hyperplane with a large margin (left) versus that of a small margin (right)



## Recursive Feature Elimination (RFE)

Simply a parameter sensitivity analysis

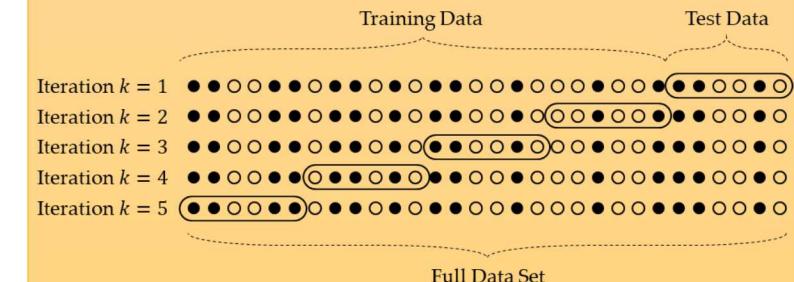
Tests removal of least sensitive features to minimize features necessary to accurately predict the classification



## Stratified K Fold Cross-Validation

Makes sure all the data is used in training and testing

Semi-random partitioning of data so that all data (including each classification) is used once in the training and once in the testing of the model



# PREDICTIONS & CONFIDENCE

## Pinholes

Classification	0.94±0.01
Optimal Features	viscosity, substrate

- Viscosity
  - Higher viscosity resists complete filling of gravure cells
  - Multiple components including particle size, shape, loading, temperature, etc.
- Substrate
  - Porosity difference between paper and plastic
  - Surface energy variation causing incomplete wetting or dewetting mechanics

## Striations

Classification	0.87±0.05
Optimal Features	particle size, cell depth, print speed

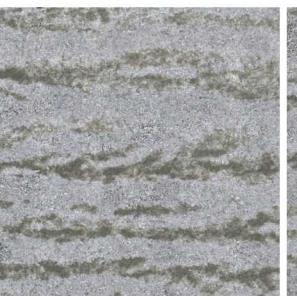
- Particle Size
  - Unexpected result from the ML
  - Fewer large particles fit in a cell
  - Reduced mobility affecting leveling when drying
- Cell Depth
  - Smaller cells deposit thinner films that dry before particles can level
- Print Speed
  - Main ribbing instability criterion

Managing cell to substrate transfer vital

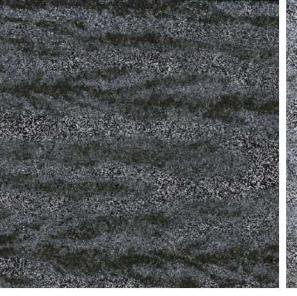
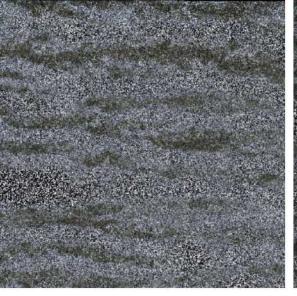
Ribbing consistent with critical features

PRINT SPEED (CM/MIN)

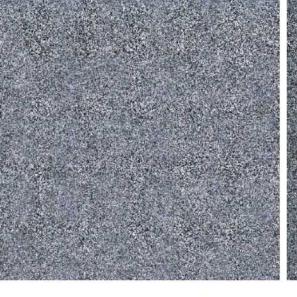
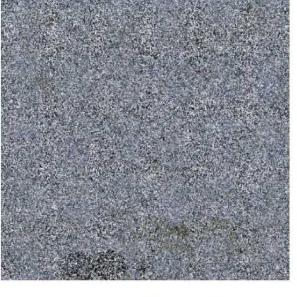
4000



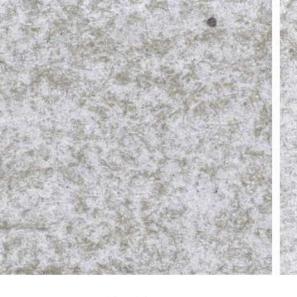
3000



2000



1000



60

70

75

80

85

90

95

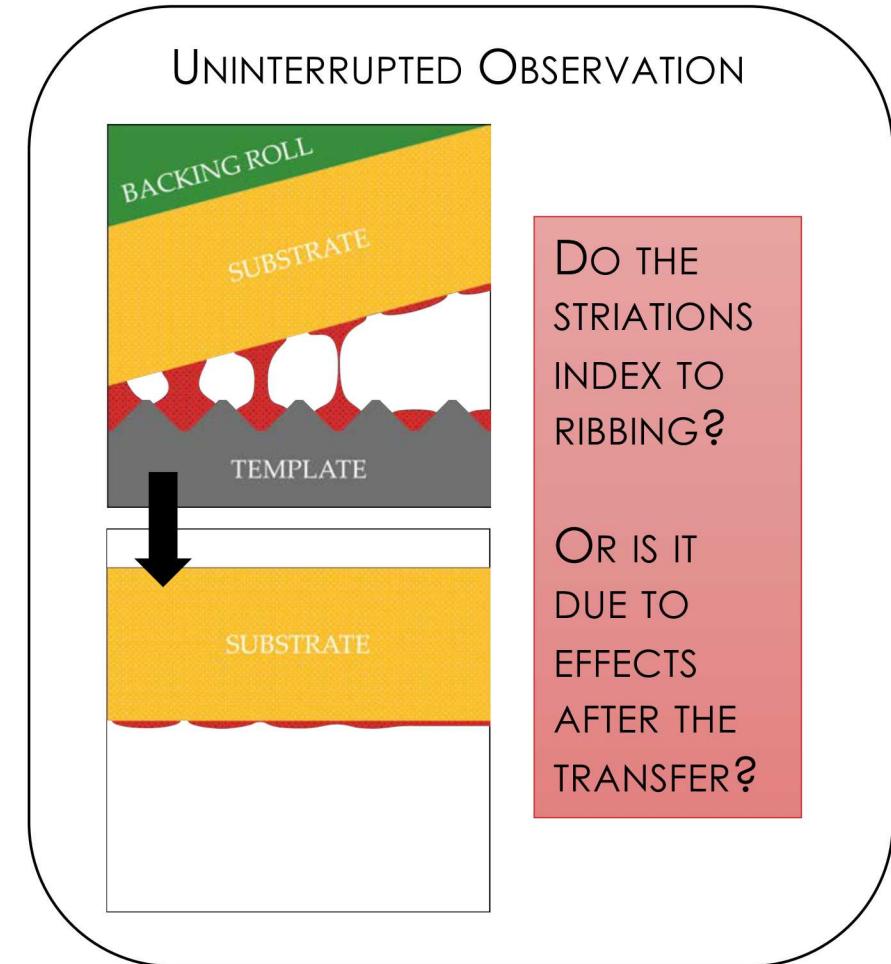
100

Cell depth and print speed  
effects observed during printing

CELL DEPTH (% OF 40  $\mu$ M)

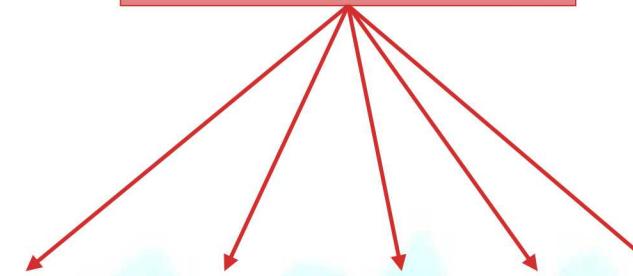
# HIGH SPEED VISUALIZATION OF TRANSFER

- Observe transfer process *in situ*
- Maintain view of transferred material
- Observe spreading

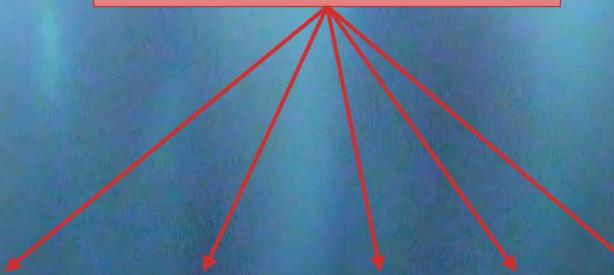


## Ribbing into striation visualization

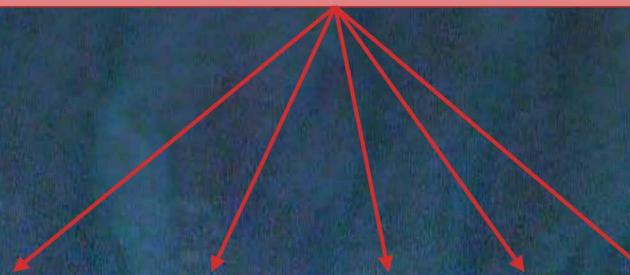
Ribs in transfer nip



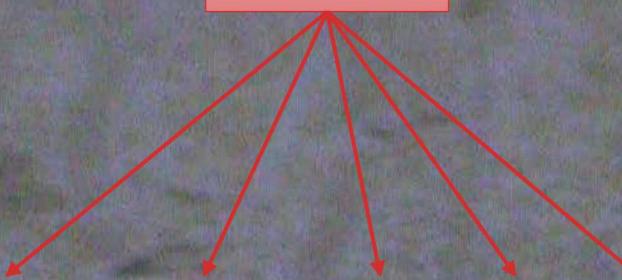
Ribs depositing ink



Peaks and troughs on substrate



Striations



# ACKNOWLEDGEMENTS

- Lena Hoover
- Sebastian Valencia
- Chris Wall
- Steven Koskey
- Kristianto Tjiptowidjojo
- Randall Schunk

## Work supported primarily by NSF:

This work is based upon work supported primarily by the National Science Foundation under cooperative Agreement No. EEC-1160494. Any opinions, findings and conclusions or recommendations expressed in this material are those of the author(s) and do not necessarily reflect the views of the National Science Foundation.

## Work supported partially by DOE/EERE/Advanced Manufacturing Office